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APPLICATION NO. FILING DATE FIRST NAMED INVENTOR ATTORNEY DOCKET NO. CONFIRMATION NO. 09/884,451 06/19/2001 Robert Dolan 101361-0043 1957 05/28/2004 EXAMINER NUTTER, MCCLENNEN & FISH, LLP MALDONADO, JULIO J Reza Mollaaghababa One International Place ART UNIT PAPER NUMBER Boston, MA 02110-2699 2823

DATE MAILED: 05/28/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)
Offic Action Summary	09/884,451	DOLAN ET AL.
	Examin r	Art Unit
	Julio J. Maldonado	
The MAILING DATE of this communication a Period for Reply	appears on the cover shet w	ith the correspondence address
A SHORTENED STATUTORY PERIOD FOR REF THE MAILING DATE OF THIS COMMUNICATION Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication. If the period for reply specified above is less than thirty (30) days, a re If NO period for reply is specified above, the maximum statutory perio Failure to reply within the set or extended period for reply will, by state Any reply received by the Office later than three months after the mail earned patent term adjustment. See 37 CFR 1.704(b).	PLY IS SET TO EXPIRE 3 M N. 1.136(a). In no event, however, may a re eply within the statutory minimum of thirt od will apply and will expire SIX (6) MON	ONTH(S) FROM eply be timely filed y (30) days will be considered timely. THS from the mailing date of this communication.
Status	*	
1) Responsive to communication(s) filed on <u>07</u> .	January 2004	
	is action is non-final.	
3) Since this application is in condition for allows	ance except for formal matter	
closed in accordance with the practice under	Ex parte Quavle 1935 C.D.	11, 453 O.C. 242
Disposition of Claims	- Parte dadyie, 1000 C.D.	11, 455 O.G. 213.
4) Claim(s) 1,6-13 and 20-25 is/are pending in the	he application.	•
4a) Of the above claim(s) is/are withdra 5)⊠ Claim(s) <u>10 and 11</u> is/are allowed.	awn from consideration.	•
6) Claim(s) <u>1,6-9,12,13 and 20-25</u> is/are rejected		
7) Claim(s) is/are objected to.	3.	
8) Claim(s) are subject to restriction and/o	*	
	or election requirement.	
Application Papers		·
9) The specification is objected to by the Examine	er.	
10)∐ The drawing(s) filed on is/are: a)☐ acc	cepted or b) objected to by	/ the Examiner
Applicant may not request that any objection to the	drawing(s) be held in abevance	See 37 CED 4 05(a)
repracement drawing sneet(s) including the correct	ion is required if the drawing (-)	13- 13- 1- 1- 1
11) The oath or declaration is objected to by the Ex	caminer. Note the attached C	Office Action or form PTO-152
Priority under 35 U.S.C. § 119		10-102.
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:	phority under 35 U.S.C. § 1	19(a)-(d) or (f).
1. Certified copies of the priority documents	s hava haan maasiya d	•
2. Certified copies of the priority documents	s have been received.	
3. Copies of the certified copies of the prior	ity documents have have	lication No
application from the International Bureau	(PCT Rule 17 2/5))	ceived in this National Stage
* See the attached detailed Office action for a list of	of the certified copies not re-	political
, and a second s	or the certified copies flot ret	ceived.
itachment(s)		
Notice of References Cited (PTO-892)	4) Dinterview Sum	mary (PTO-413)
Notice of Droftenson	TO LESS OF THE PROPERTY AND THE PROPERTY	
Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	Paper No(s)/Ma	nal Patent Application (PTO-152)

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DETAILED ACTION

1. The cancellation of claims 2-5 and 14-19 is acknowledged.

Allowable Subject Matter

2. The indicated allowability of claims 12 and 13 is withdrawn in view of the newly discovered reference(s) to Dolan et al. (U.S. 6,248,642 B1). Rejections based on the newly cited reference(s) follow.

Continued Examination Under 37 CFR 1.114

3. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 01/07/2004 has been entered.

Claim Rejections - 35 USC § 103

- 4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 5. Claims 1, 6-9 and 20-25 are rejected under 35 U.S.C. 103(a) as being unpatentable over Sakaguchi et al. (U.S. 6,313,014 B1) in view of Ogura et al. (U.S. 6,506,662 B2).

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In reference to claims 1 and 20-25, Sakaguchi et al. (Fig.1-5) in a related method to form buried oxide films teach placing the substrate (23) into a vacuum chamber, the substrate being treated with a background fluid other than molecular oxygen, said fluid comprising hydrogen and said hydrogen is a surface inhibiting agent; evacuating the vacuum chamber to a first pressure; and implanting ions into the substrate (23) to form a buried oxide layer under a top silicon layer (22), where the fluid inhibits formations of threading dislocations in the top silicon layer (22) for reducing a defect density of the processed substrate; and selecting the fluid from fluids that inhibit formations of threading dislocations in the top silicon layer (22) for reducing a defect density of the processed substrate (23) (column 2, line 53 – column 16, line 25).

Sakaguchi et al. fail to teach introducing a fluid other than molecular oxygen in a vacuum chamber as a background fluid.

However, Ogura et al. (Figs.1C-3) in a related method to form a buried oxide layer by ion irradiation teach dissociating water molecules (H_2O) in a plasma chamber to obtain positive ions; and introducing said ions into a reaction chamber where the substrate to be implanted is provided therein, wherein said ions include oxygen ions and a fluid other than oxygen comprising hydrogen (column 3,lines 60-65, column 4, lines 1-4, column 8, line 61- column 9, line 2 and column 9, lines 54-62). Furthermore, Ogura et al. teach that the introduction of said oxygen ions and said fluid occurs before said implantation of said oxygen ions. Therefore, Ogura et al. teach introducing a fluid other than molecular oxygen into the reaction chamber; and subsequently, implanting ions into the substrate, in the presence of the background fluid. It would have been

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within the scope of one of ordinary skill in the art to combine the teachings of Sakaguchi et al. and Ogura et al. to enable the implantation step of Sakaguchi et al. to be performed according to the teachings of Ogura et al. because one of ordinary skill in the art at the time the invention was made would have been motivated to look to alternative suitable methods of performing the disclosed implantation step of Sakaguchi et al. and art recognized suitability for an intended purpose has been recognized to be motivation to combine. MPEP 2144.07.

In reference to claims 6 and 7, Sakaguchi et al. in combination with Ogura et al. substantially teach all aspects of the invention but fail to teach the first pressure is less than about 1x10⁻⁵ Torr and a second pressure less than about 1x10⁻³. However, the examiner takes official notice that the selection of the claimed ranges is obvious because it is a matter of determining optimum process condition by routine experimentation with a limited number of species.

In reference to claims 8 and 9, Sakaguchi et al. in combination with Ogura et al. teach controlling the amount of fluid introduced into the vacuum chamber based upon a parameter measured in the chamber, said parameter consisting from the group consisting of ion concentration and temperature (column 2, line 53 – column 16, line 25).

Allowable Subject Matter

- 6. Claims 10 and 11 are allowed.
- 7. The following is a statement of reasons for the indication of allowable subject matter: the prior art of record neither teaches nor suggests the step of actively

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controlling the amount of fluid introduced into the vacuum chamber based upon a measurement of an ion beam current.

Response to Arguments

8. Applicant's arguments filed 01/07/2004 have been fully considered but they are not persuasive.

Applicants argue, "... Ogura fails to bridge the gap in the teachings of Sakaguchi to render the claimed inventions obvious.... Ogura, describes a method of generating a silicon-on-insulator substrate by utilizing an apparatus that includes a plasma chamber in which plasma dissociation of selected gas molecule is utilized to generate ions, and further includes a separate reaction chamber in which a silicon substrate is exposed to ions, which were extracted form the plasma chamber...". In response to this argument, as mentioned above, one of ordinary skill in the art at the time the invention was made would have been motivated to look to alternative suitable methods of performing the disclosed implantation step of Sakaguchi et al. and art recognized suitability for an intended purpose has been recognized to be motivation to combine. MPEP 2144.07.

Also, applicants argue, "... Ogura does not teach introducing a fluid other than molecular oxygen into the reaction chamber prior to implanting ions in the silicon substrate...Such contaminant ions form part of the ion beam bombarding the substrate, and not a background fluid that is distinct from the ion beam. In addition, these contaminant ions are introduced into the reaction chamber at the same time as the oxygen ions, and not prior to implantation of the oxygen ions into the substrate....". In response to these arguments, the ionized gases in Ogura et al. have to be introduced

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first into the reaction chamber before the oxygen ions are implanted in the substrate. Therefore, Ogura et al. teach introducing a fluid other than molecular oxygen in the reaction chamber and subsequently implanting the oxygen into the substrate. The plasma would no occur in the absence of these gases. Furthermore, there is no description in the rejected claims that the fluid other than oxygen has to be different from the ion beam. In response to applicant's argument that the references fail to show certain features of applicant's invention, it is noted that the features upon which applicant relies are not recited in the rejected claim(s). Although the claims are interpreted in light of the specification, limitations from the specification are not read into the claims. See *In re Van Geuns*, 988 F.2d 1181, 26 USPQ2d 1057 (Fed. Cir. 1993).

Conclusion

- 9. Any inquiry of a general nature or relating to the status of this application should be directed to the Group Receptionist whose telephone number is 571-272-2800. See MPEP 203.08.
- 10. Any inquiry concerning this communication or earlier communications from the examiner should be directed to examiner Julio J. Maldonado whose telephone number is (571) 272-1864. The examiner can normally be reached on Monday through Friday.
- 11. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Olik Chaudhuri, can be reached on (571) 272-1855. The fax number for this group is 703-872-9306 for before final submissions, 703-872-9306 for after final submissions and the customer service number for group 2800 is (703) 306-3329. Updates can be found at http://www.uspto.gov/web/info/2800.htm.

Julio J. Maldonado

May 8, 2004

Julio J. Maldonado Patent Examiner Art Unit 2823

George Fourson
Primary Examiner